



# DEPFET Active Pixel Sensors for the ILC

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*for the DEPFET Collaboration  
([www.depfeat.org](http://www.depfeat.org))*



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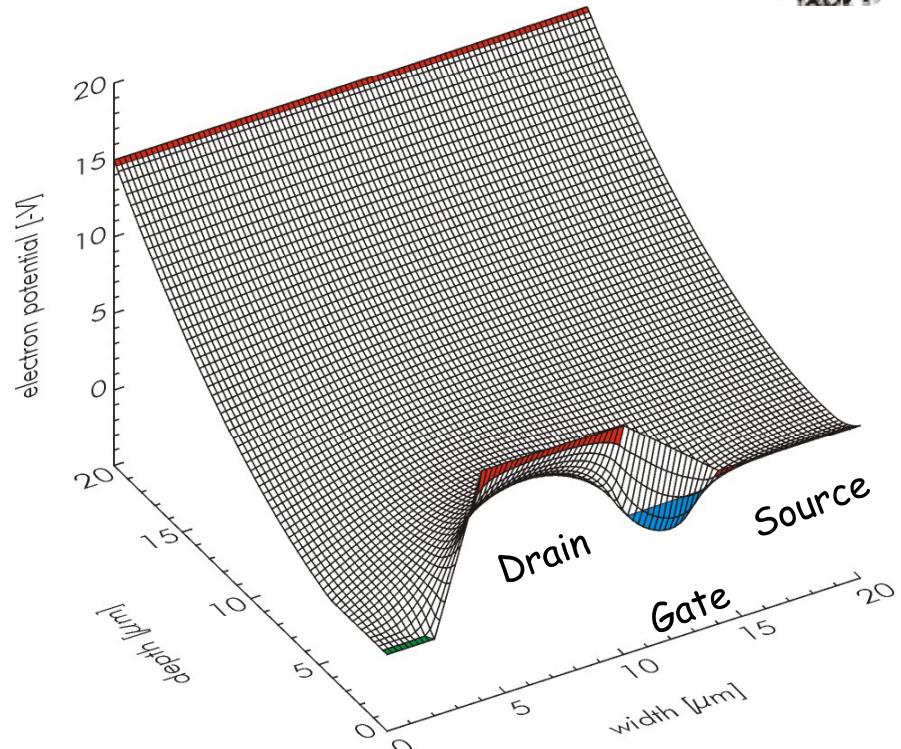
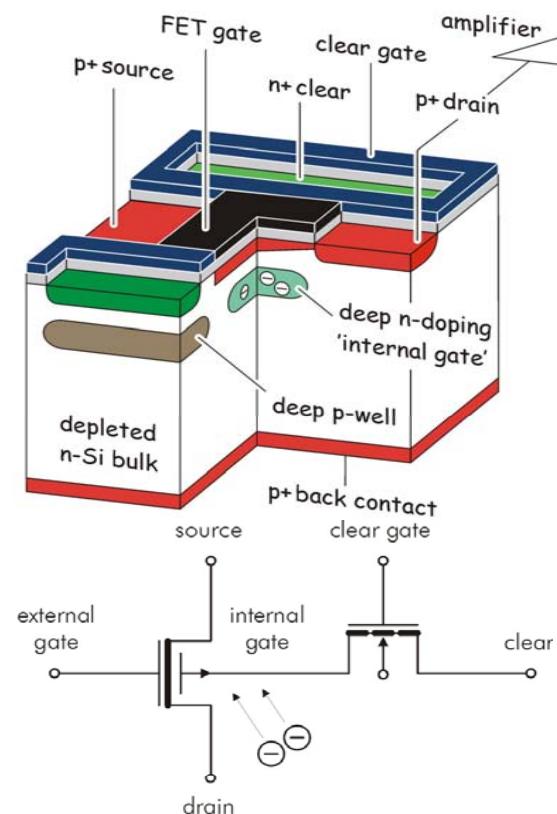


## DEPFET Principle

J. Kemmer & G. Lutz, 1987

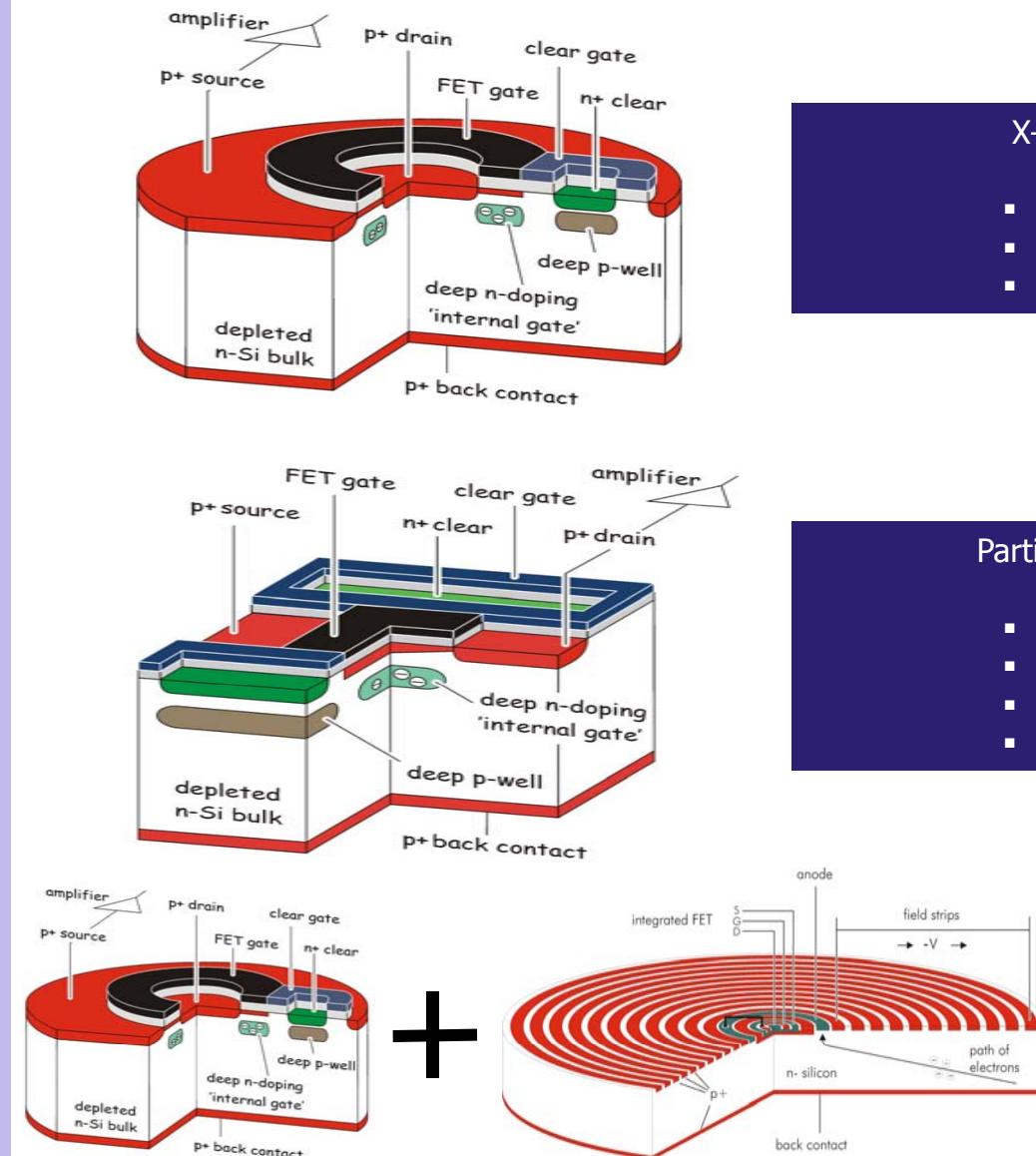


DEpleted P-channel FET



- fully depleted sensitive volume, charge collection by drift
- internal amplification → q-I conversion:  $0.4 \text{ nA/e}$ , scales with gate length and bias current
- Charge collection in "off" state, read out on demand

## ● Overview: Types and Applications



X-ray imaging spectroscopy → XEUS

- pixel size:  $100\mu\text{m}$
- r/o time per row:  $2.5 \mu\text{s}$
- Noise:  $\approx 4 \text{ el ENC}$

Particle tracking → vertex detector at ILC

- pixel size:  $24\mu\text{m}$
- r/o time per row:  $25$
- Noise:  $\approx 100 \text{ el ENC}$
- thin detectors:  $\approx 50\mu\text{m}$

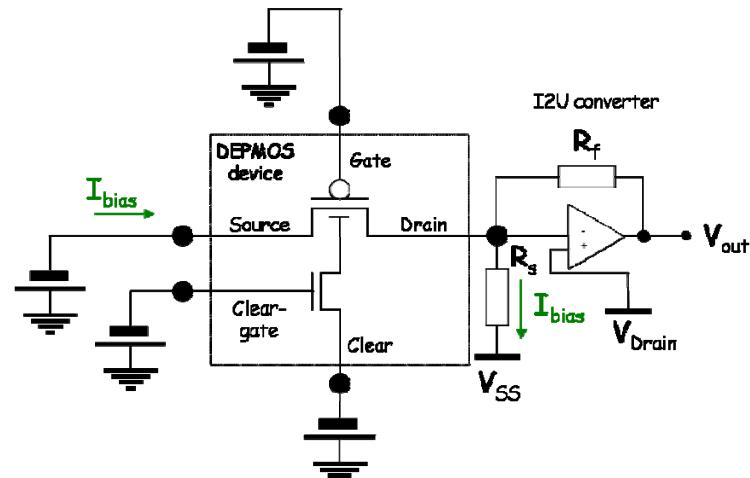
DEPFET MacroPixel  
X-ray (imaging) spectroscopy  
→ BepiColombo, SimbolX

- pixel size:  $100\text{s of }\mu\text{m}$

## ● DEPFET Array - read-out at the ILC

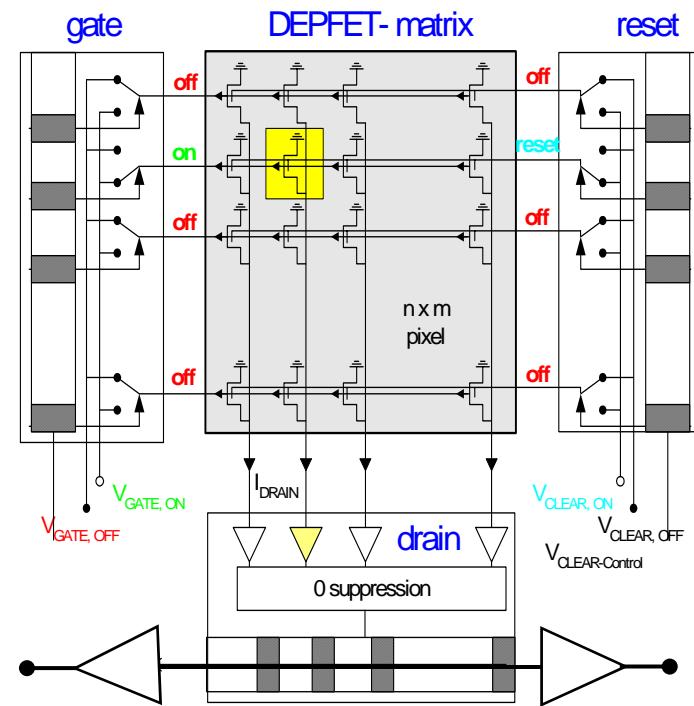


Drain read out

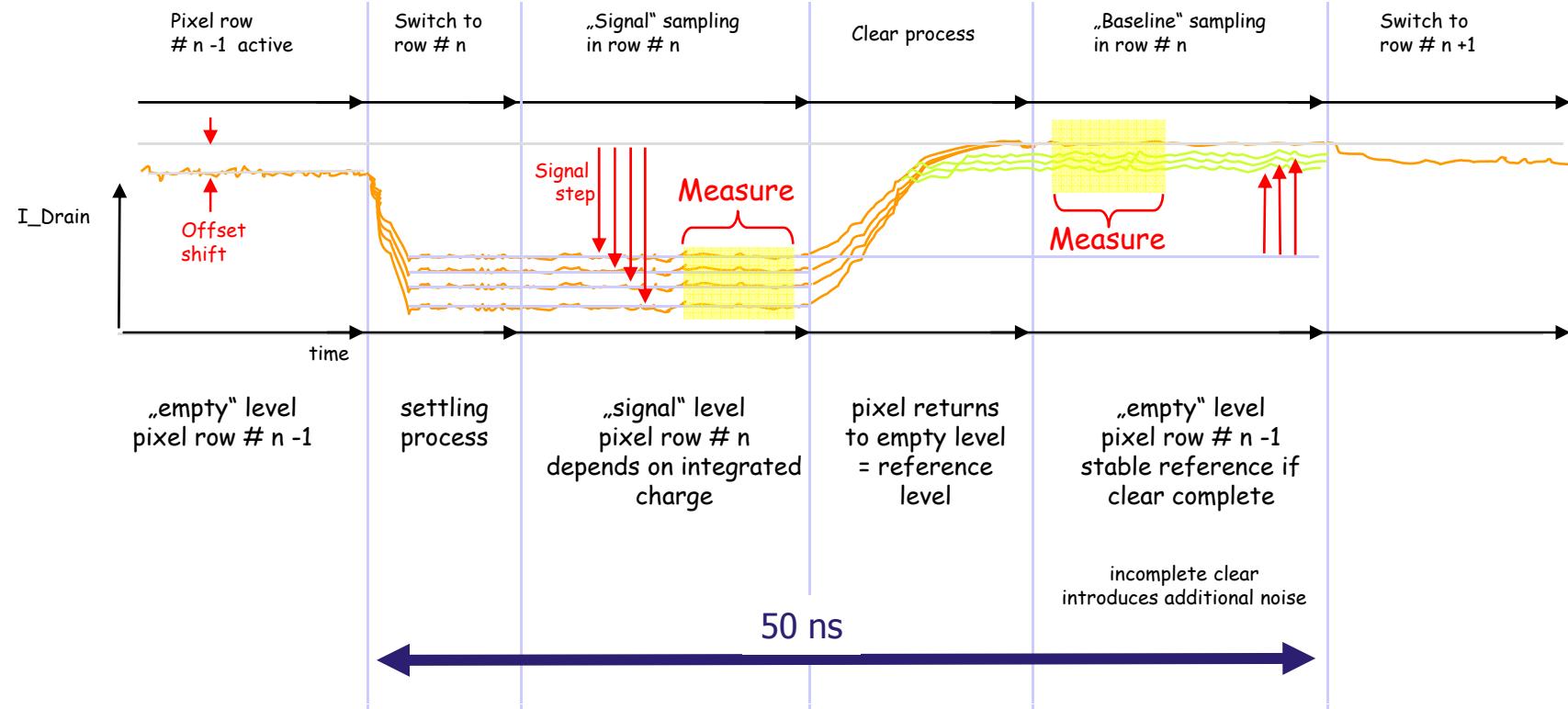


Row wise read-out ("rolling shutter")

- select row with external gate, read current, clear DEPFET, read current again → the difference is the signal
- Low power consumption
- two different auxiliary ASICs needed
- limited frame rate
- cap. load at the f/e adds noise

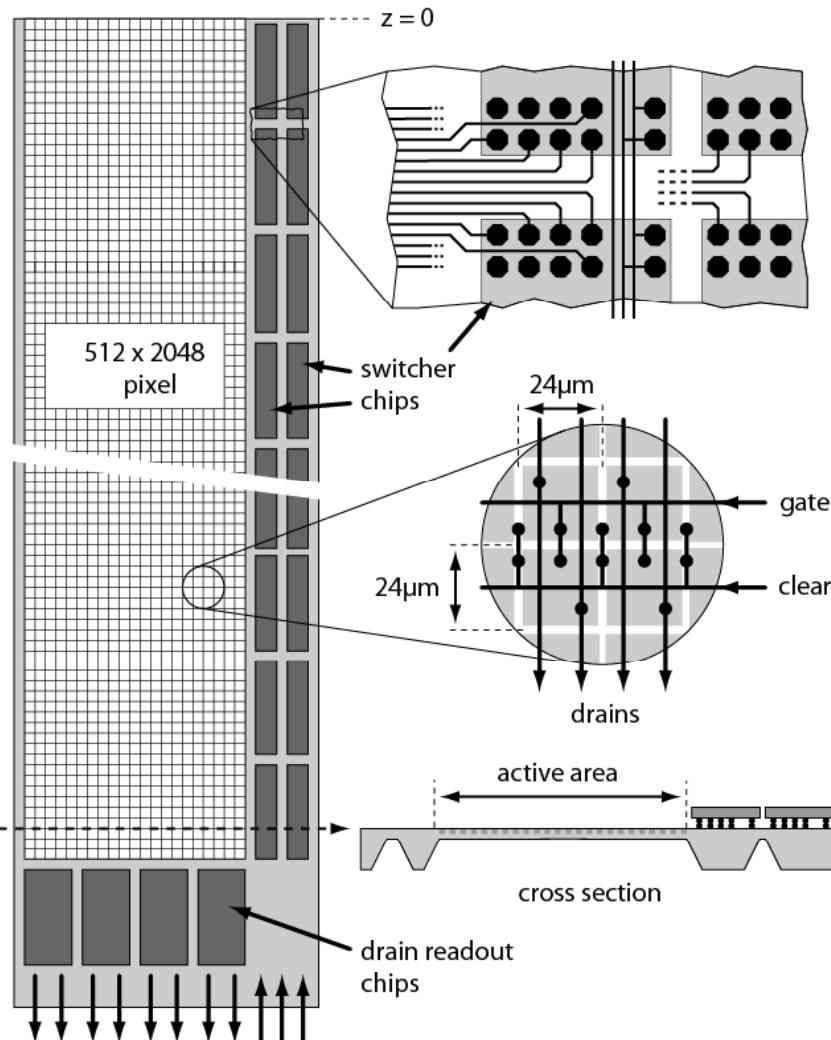


## Row wise read-out → matrix signal



- Row wise CDS, time between the two samples ~10 ns!
- However, we need (almost..) complete clear → Hans-Günther's talk..

## ● ILC VXD baseline design



Just as a starting point for the R&D!

- 5 layer, old TESLA layout
- 10 and 25 cm long ladders read out at the ends
- 24 micron pixel
- design goal 0.1%  $X_0$  per layer in the sens. region

Strategy to cope with the background:

- read ~20 times per train
- store data on ladder
- transfer the data off ladder in the train pause  
→ row rate of 40 MHz
- read two rows in parallel, doubles # r/o channels but:  
→ row rate 20 MHz ☺

- Work sharing in the collaboration



	DEPFET/Ladder Sim. and Irrad.	Auxiliary ASICs Development	System Development	System Tests and Test Beams
Aachen			X	
Bonn		X	X	X
Karlsruhe	X			
Mannheim		X	X	X
Munich	X			X
Prague			X	X
Valencia			X	X

### The next 120 minutes

- o Hans-Guenther: DEPFET Design and Test, Radiation Tolerance, Ladder Concept
- o Ivan: ASICs: Steering and f/e ASIC
- o Carlos: Test of the Prototype System
- o Ariane: ILC VXD Simulation

### Summary and Future Plans